



XP9976GM

Halogen-Free Product

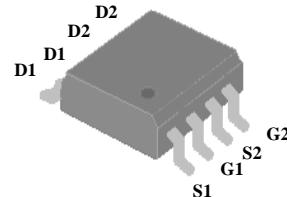
DUAL N-CHANNEL ENHANCEMENT
MODE POWER MOSFET

▼ Lower On-resistance

▼ Simple Drive Requirement

▼ Fast Switching Characteristic

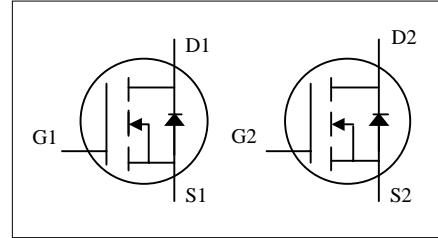
▼ RoHS Compliant & Halogen-Free



BV _{DSS}	60V
R _{DS(ON)}	20.5mΩ
I _D	7.6A

Description

XP9976 series are innovated design and silicon process technology to achieve the lowest possible on-resistance and fast switching performance. It provides the designer with an extreme efficient device for use in a wide range of power applications.



The SO-8 package is widely preferred for all commercial-industrial surface mount applications using infrared reflow technique and suited for voltage conversion or switch applications.

Absolute Maximum Ratings@T_j=25°C(unless otherwise specified)

Symbol	Parameter	Rating	Units
V _{DS}	Drain-Source Voltage	60	V
V _{GS}	Gate-Source Voltage	+20	V
I _D @T _A =25°C	Drain Current, V _{GS} @ 10V ³	7.6	A
I _D @T _A =70°C	Drain Current, V _{GS} @ 10V ³	6	A
I _{DM}	Pulsed Drain Current ¹	40	A
P _D @T _A =25°C	Total Power Dissipation	2	W
T _{STG}	Storage Temperature Range	-55 to 150	°C
T _J	Operating Junction Temperature Range	-55 to 150	°C

Thermal Data

Symbol	Parameter	Value	Unit
R _{thj-a}	Maximum Thermal Resistance, Junction-ambient ³	62.5	°C/W

Electrical Characteristics @ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	60	-	-	V
$R_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance ²	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=6\text{A}$	-	-	20.5	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}, I_{\text{D}}=4\text{A}$	-	-	38	$\text{m}\Omega$
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	1	-	3	V
g_{fs}	Forward Transconductance	$V_{\text{DS}}=10\text{V}, I_{\text{D}}=6\text{A}$	-	5.9	-	S
I_{DSS}	Drain-Source Leakage Current	$V_{\text{DS}}=48\text{V}, V_{\text{GS}}=0\text{V}$	-	-	25	uA
	Drain-Source Leakage Current ($T_j=70^\circ\text{C}$)	$V_{\text{DS}}=48\text{V}, V_{\text{GS}}=0\text{V}$	-	-	100	uA
I_{GSS}	Gate-Source Leakage	$V_{\text{GS}}=\pm 20\text{V}, V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
Q_g	Total Gate Charge	$I_{\text{D}}=6\text{A}$	-	30	50	nC
Q_{gs}	Gate-Source Charge	$V_{\text{DS}}=48\text{V}$	-	4.5	-	nC
Q_{gd}	Gate-Drain ("Miller") Charge	$V_{\text{GS}}=10\text{V}$	-	10	-	nC
$t_{\text{d}(\text{on})}$	Turn-on Delay Time	$V_{\text{DS}}=30\text{V}$	-	9	-	ns
t_r	Rise Time	$I_{\text{D}}=1\text{A}$	-	6.3	-	ns
$t_{\text{d}(\text{off})}$	Turn-off Delay Time	$R_{\text{G}}=3.3\Omega$	-	28	-	ns
t_f	Fall Time	$V_{\text{GS}}=10\text{V}$	-	10	-	ns
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	1320	2100	pF
C_{oss}	Output Capacitance	$V_{\text{DS}}=25\text{V}$	-	140	-	pF
C_{rss}	Reverse Transfer Capacitance	f=1.0MHz	-	110	-	pF

Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V_{SD}	Forward On Voltage ²	$I_{\text{S}}=1.7\text{A}, V_{\text{GS}}=0\text{V}$	-	-	1.2	V
t_{rr}	Reverse Recovery Time	$I_{\text{S}}=6\text{A}, V_{\text{GS}}=0\text{V},$ $dI/dt=100\text{A}/\mu\text{s}$	-	29	-	ns
Q_{rr}	Reverse Recovery Charge		-	35	-	nC

Notes:

1. Pulse width limited by Max. junction temperature.
2. Pulse test
3. Surface mounted on 1 in² copper pad of FR4 board, t \leq 10sec ; 135 °C/W when mounted on Min. copper pad.

THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

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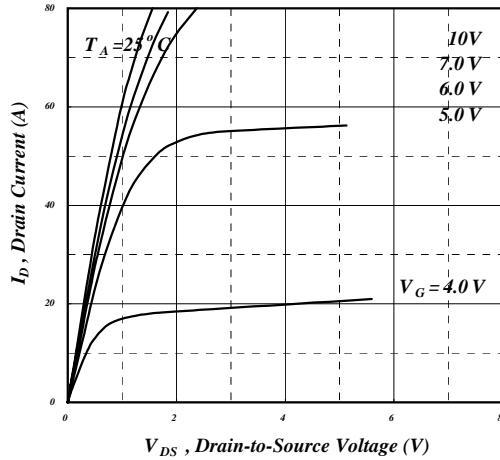


Fig 1. Typical Output Characteristics

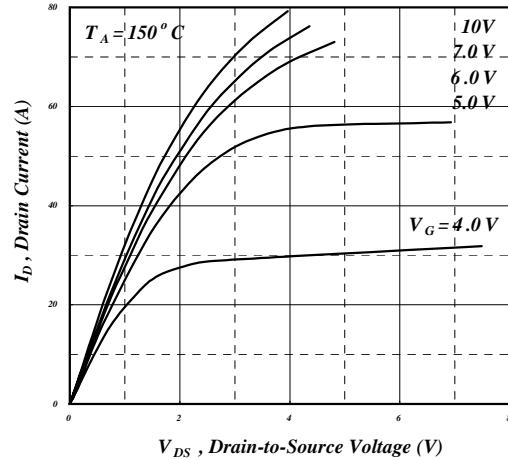


Fig 2. Typical Output Characteristics

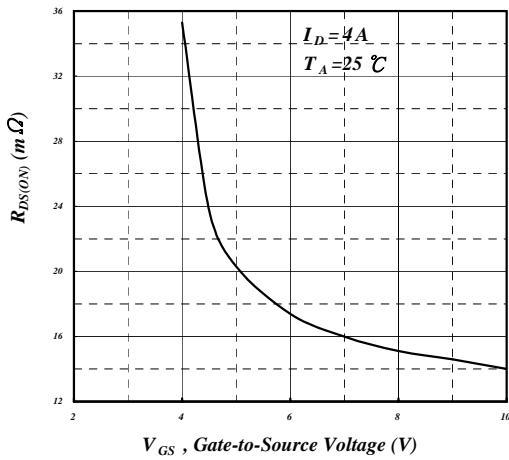


Fig 3. On-Resistance v.s. Gate Voltage

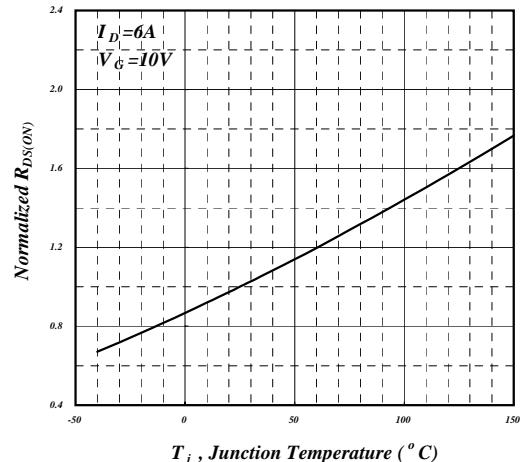


Fig 4. Normalized On-Resistance v.s. Junction Temperature

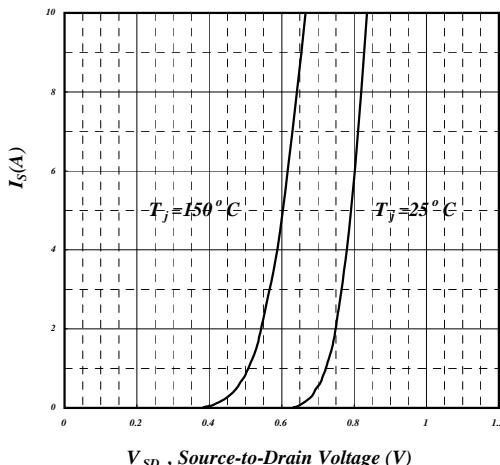


Fig 5. Forward Characteristic of Reverse Diode

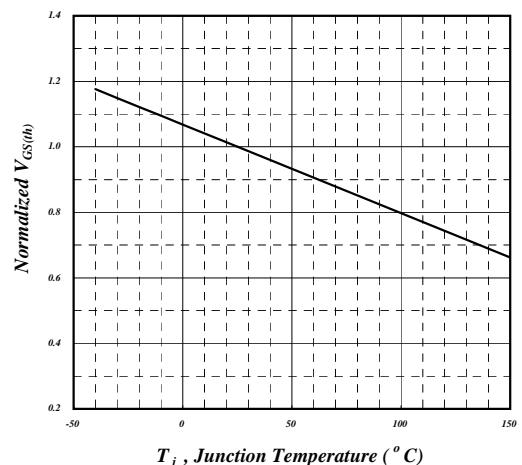


Fig 6. Gate Threshold Voltage v.s. Junction Temperature

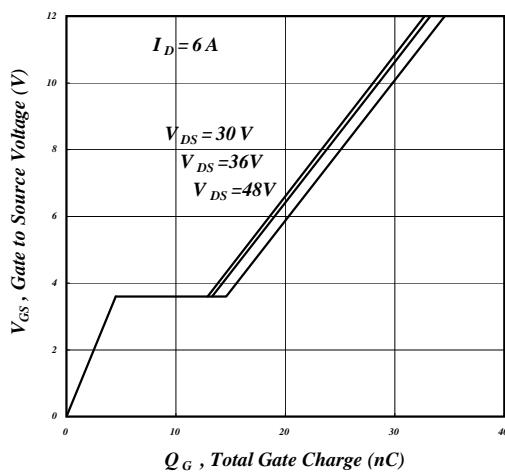


Fig 7. Gate Charge Characteristics

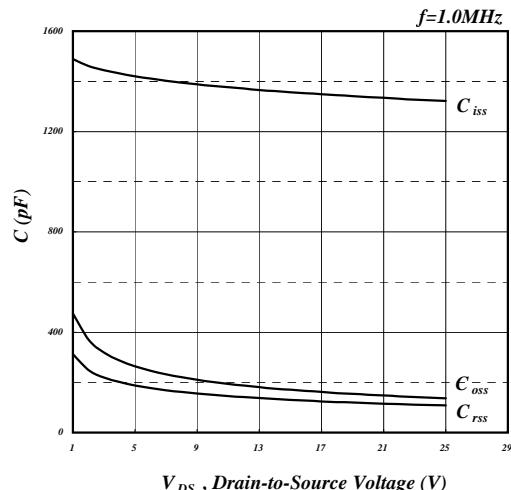


Fig 8. Typical Capacitance Characteristics

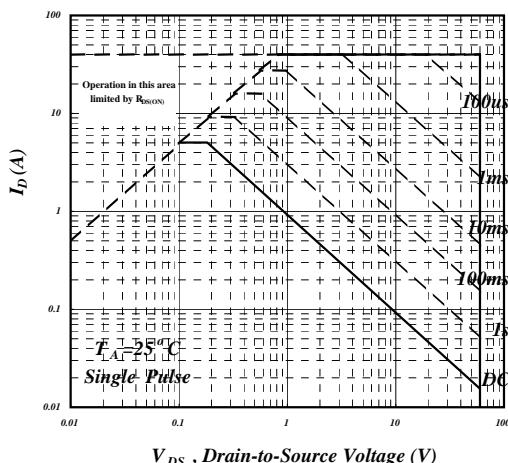


Fig 9. Maximum Safe Operating Area

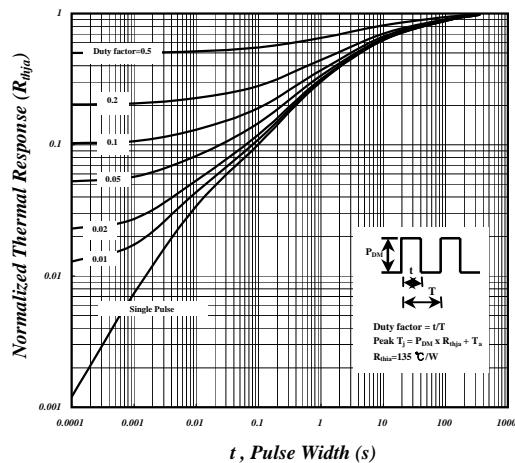


Fig 10. Effective Transient Thermal Impedance

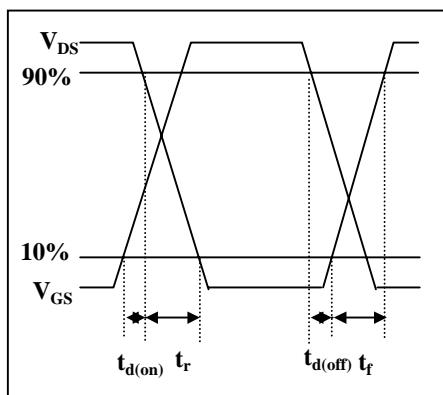


Fig 11. Switching Time Waveform

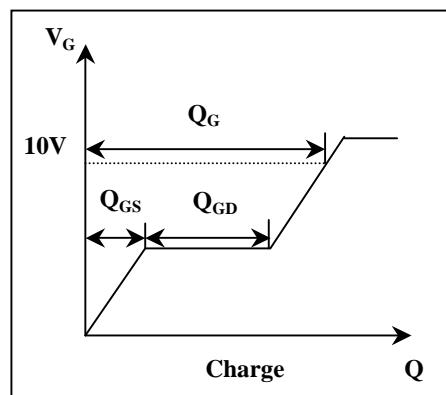
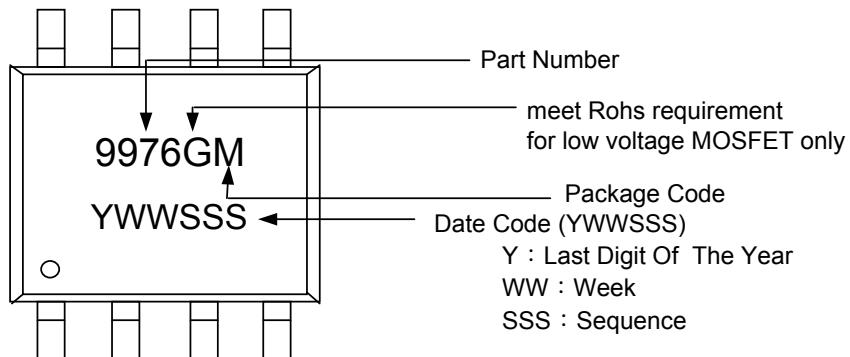
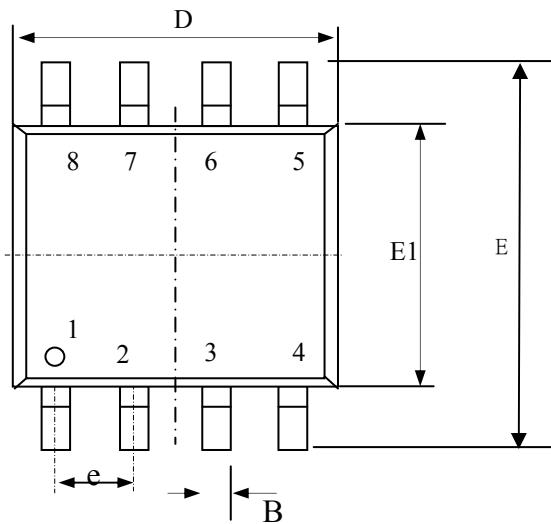


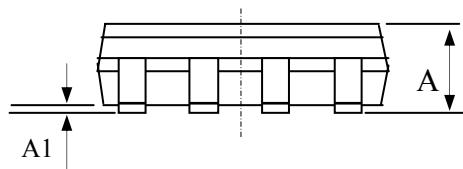
Fig 12. Gate Charge Waveform

MARKING INFORMATION

Package Outline : SO-8

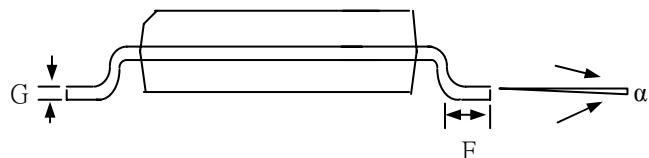


SYMBOLS	Millimeters		
	MIN	NOM	MAX
A	1.35	1.55	1.75
A1	0.05	0.15	0.25
B	0.30	0.41	0.51
D	4.80	5.05	5.30
E	5.79	6.00	6.20
E1	3.70	3.90	4.10
e	1.27 TYP		
G	0.17	0.21	0.25
F	0.38	0.83	1.27
α	0°	4°	8°



1. All Dimension Are In Millimeters.

2. Dimension Does Not Include Mold Protrusions.



SO-8 FOOTPRINT :

